

- Lecturers
- Program
- MNaF – Mission, Capabilities, Access
- 3D-Characterization
  - Story of a two-headed Rhino
  - Applications
  - Scale-bridging & Correlative Approach
  - Projection Tomography vs. Serial Sectioning

**Prof. Dr. Benjamin Butz**  
Micro- and Nanoanalytics Group LMN &  
Micro- and Nanoanalytics Facility MNaF  
University of Siegen



# Lecturers (alphabetic order)



Dr.-Ing.  
**Benjamin Apeleo Zubiri**

CT



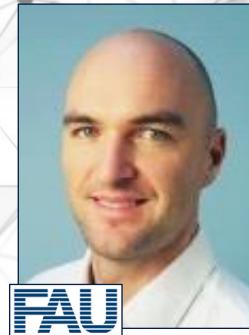
Prof. Dr.  
**Benjamin Butz**

INTRO



PhD  
**Marco Cantoni**

FIB



Prof. Dr.  
**Peter Felfer**

APT



M.Sc.  
**Xiaohui Huang**

RECON



Prof. Dr.-Ing.  
**Manuela S. Killian**

SIMS



Dr.-Ing.  
**Julian Müller**

TEM



Dr.-Ing.  
**Pascal Pinter**

EVAL

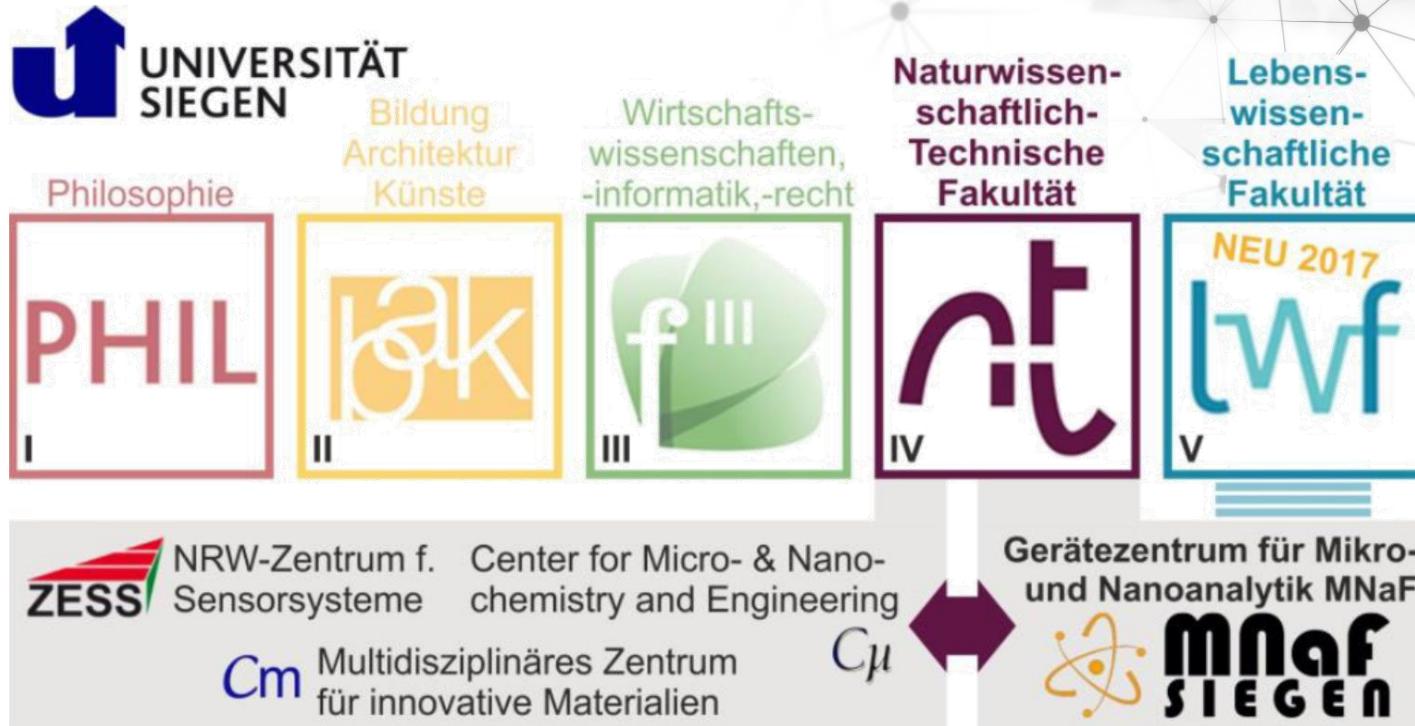
# Program

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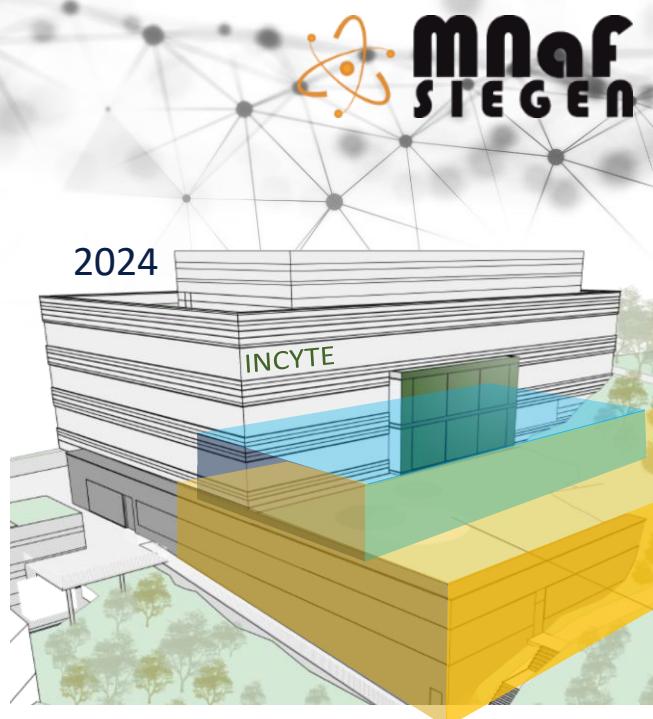
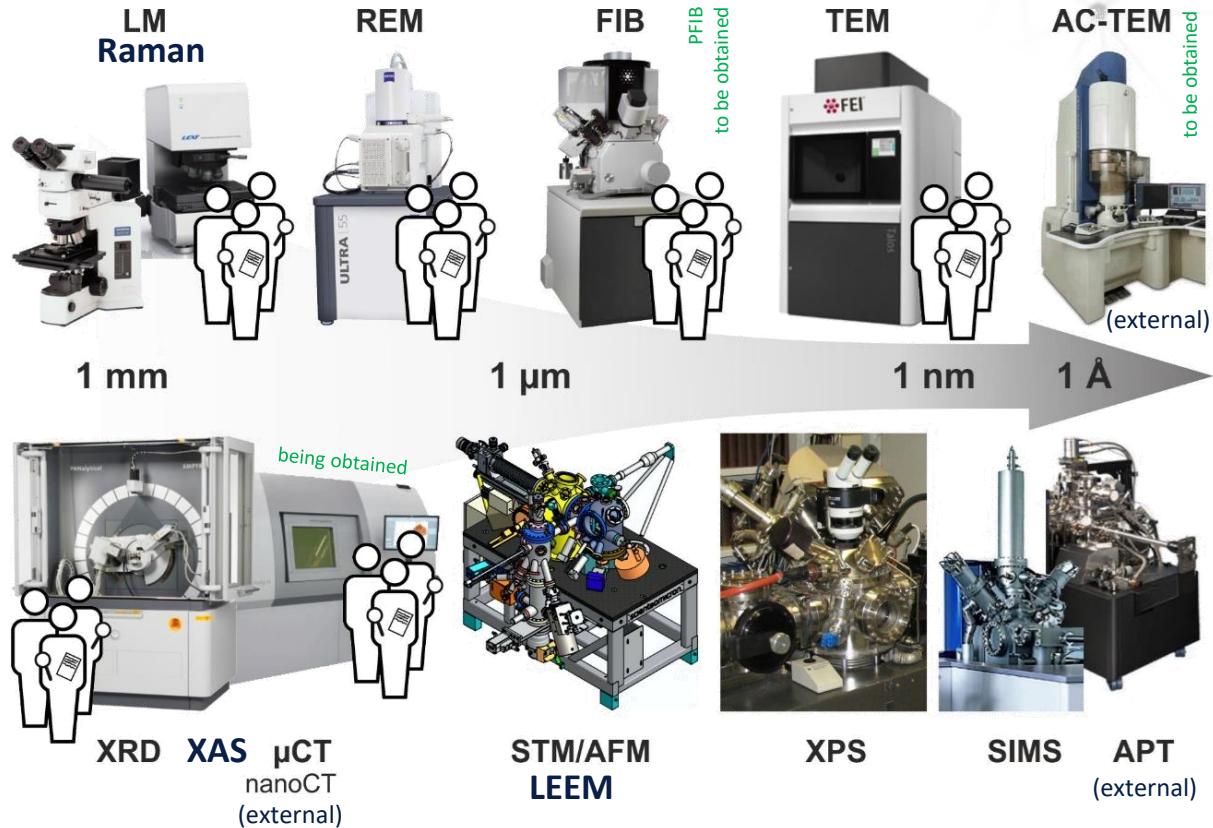
**afterwards:** 10 minutes online survey via EvaSys

# MNaF – DFG-funded Core Facility



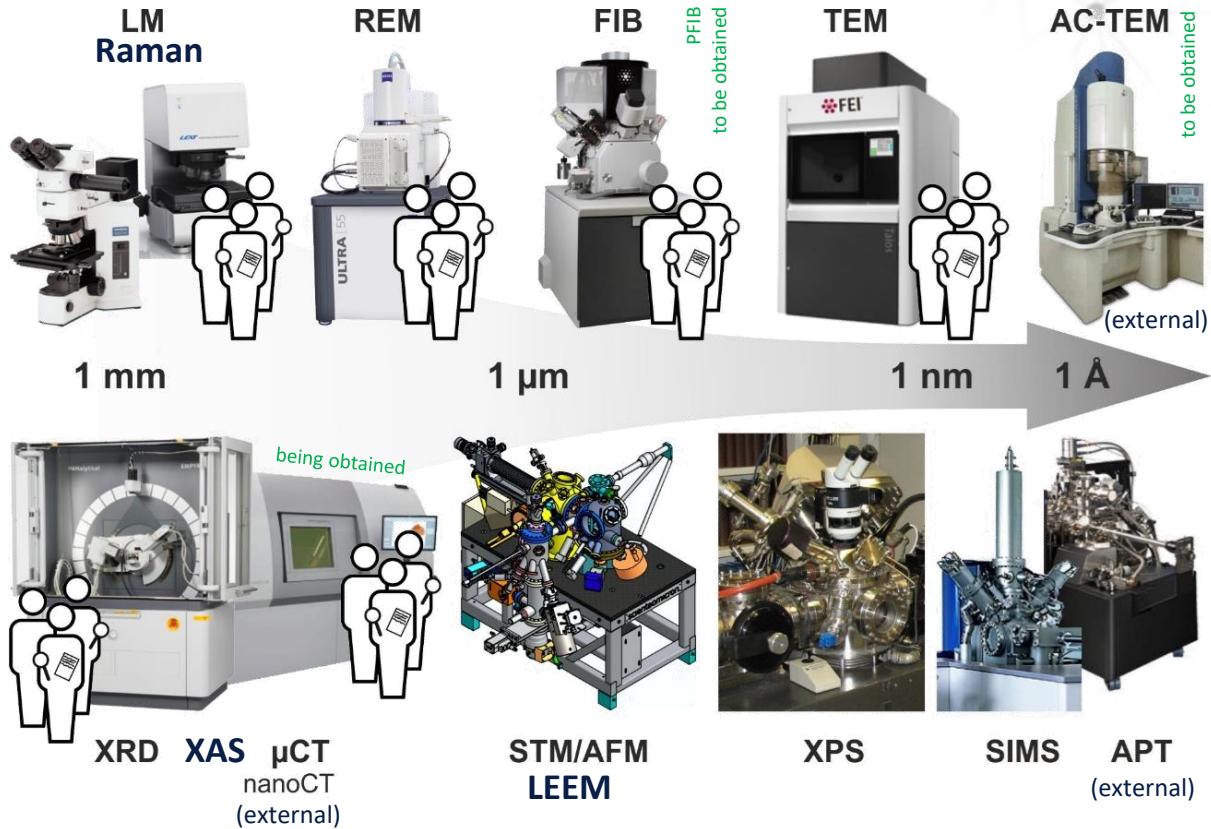
**Scientific board (10 PIs)    >100 Users    >200 Publications (past 5 years)**

# MNaF – Capabilities & Access



- 7 EM-labs
- 300 m<sup>2</sup> compl. analytics
- 300 m<sup>2</sup> sample prep
- 600 m<sup>2</sup> ISO4 cleanroom
- Group labs & offices (5.500 m<sup>2</sup> funct. space)

# MNaF – Capabilities & Access



# MNaF – User Support



## Annual Summer Schools



*SEM, FIB & ion microscopy  
TEM imaging & diffraction  
X-ray techniques (2021)*

4x 1,5h 4x 4h 3(-5) per group



TEM '18 / '19



REM/FIB & SIMS '20

A screenshot of the REM/FIB &amp; SIMS School website. It features a banner with the text "REM/FIB &amp; SIMS School June/July 2020 Universität Siegen". Below the banner are several images of microscopes and samples. To the right, there are video call windows for "Charles Ogolla", "Bogdan Okhrim...", and "Yannik Loth". On the left, there is a sidebar with various links and a small image of a person.

# Why 3D-analytics?

Two-headed rhino as new species?

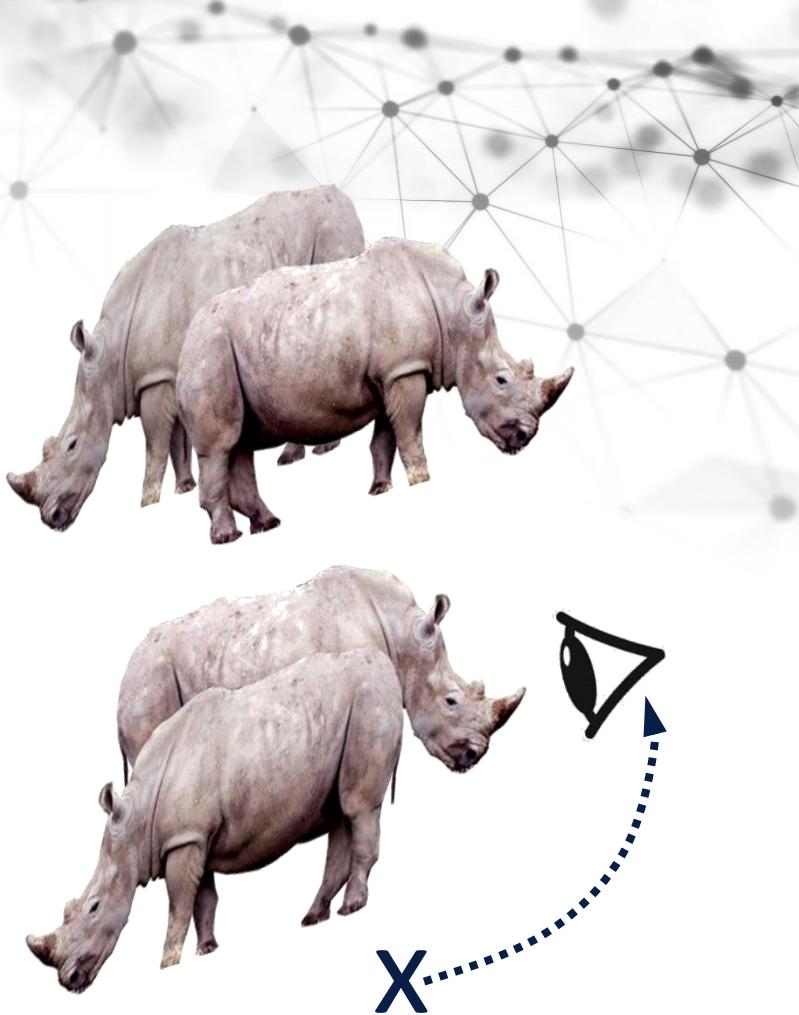


Most probably not!



serengeti-park.de, naturdetektive.de

?



# Applications

## Quality assurance

Phase distribution (composites)

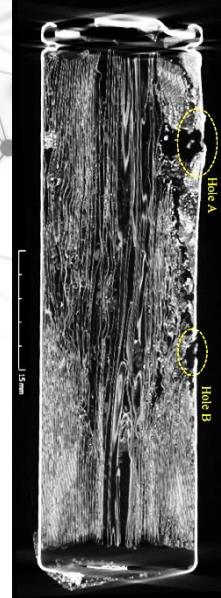
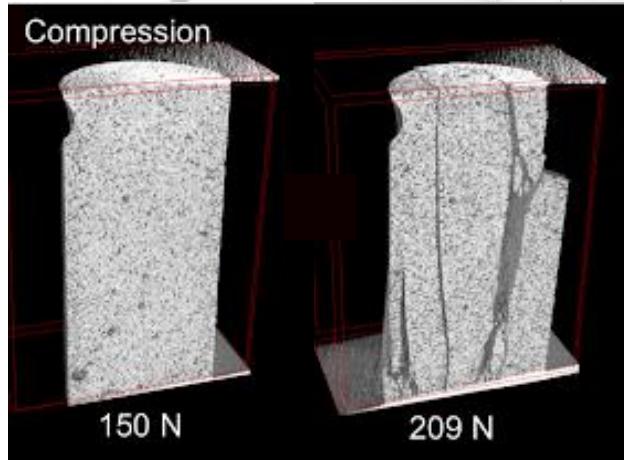
Voids, inclusions

nikonmetrology.com



**Metrology**  
Shape assurance

**Failure analysis**  
Cracks, breakdown, runaway



**Static measurements**

***in situ / in operando* analyses**

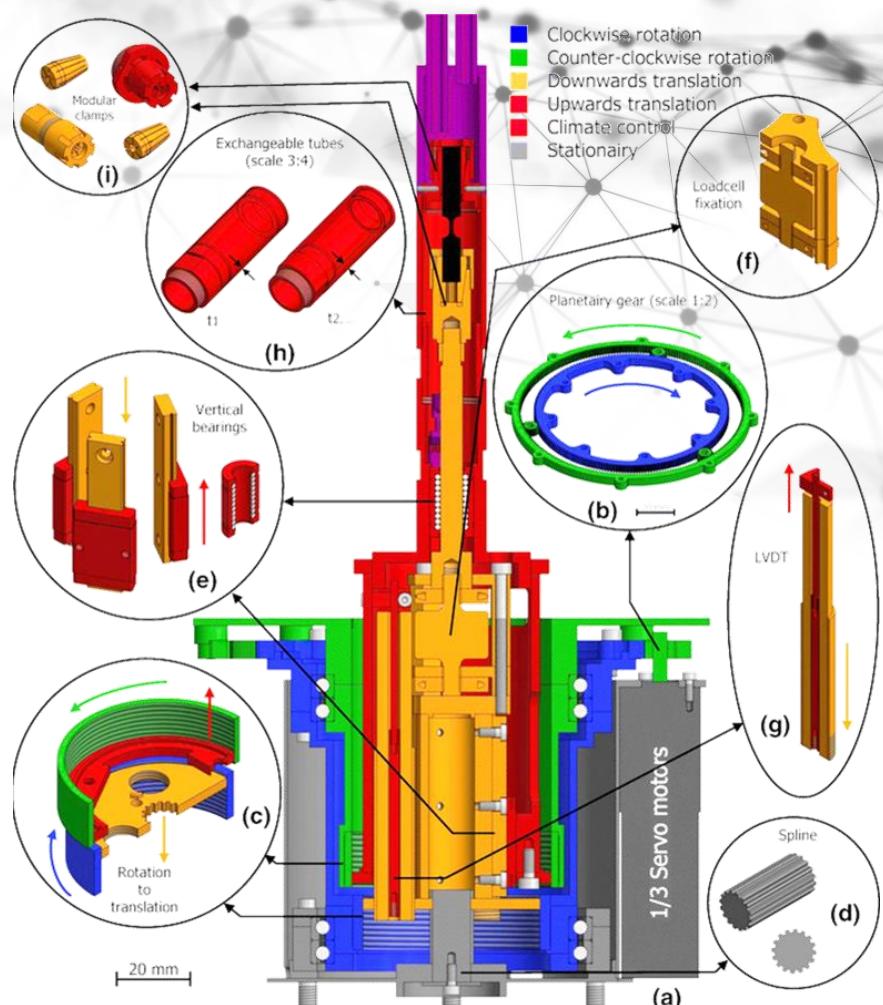
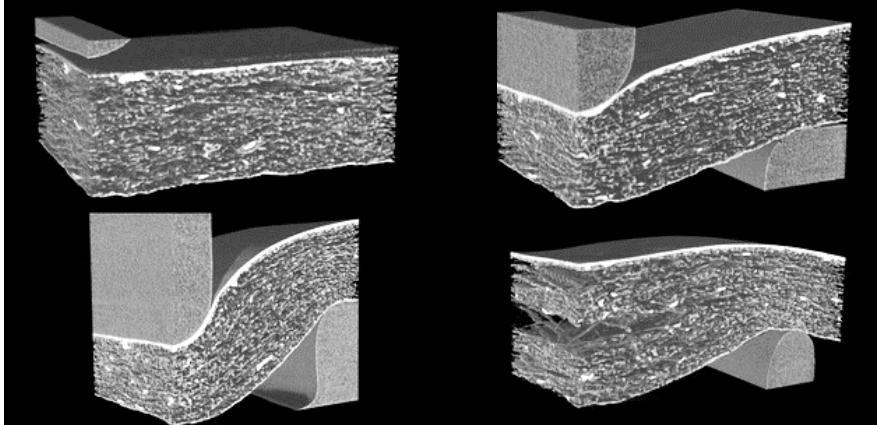
mech. load, biasing, heating, environment, ...

Kong et al, Fire Tech., 56 (2020) pp. 2565

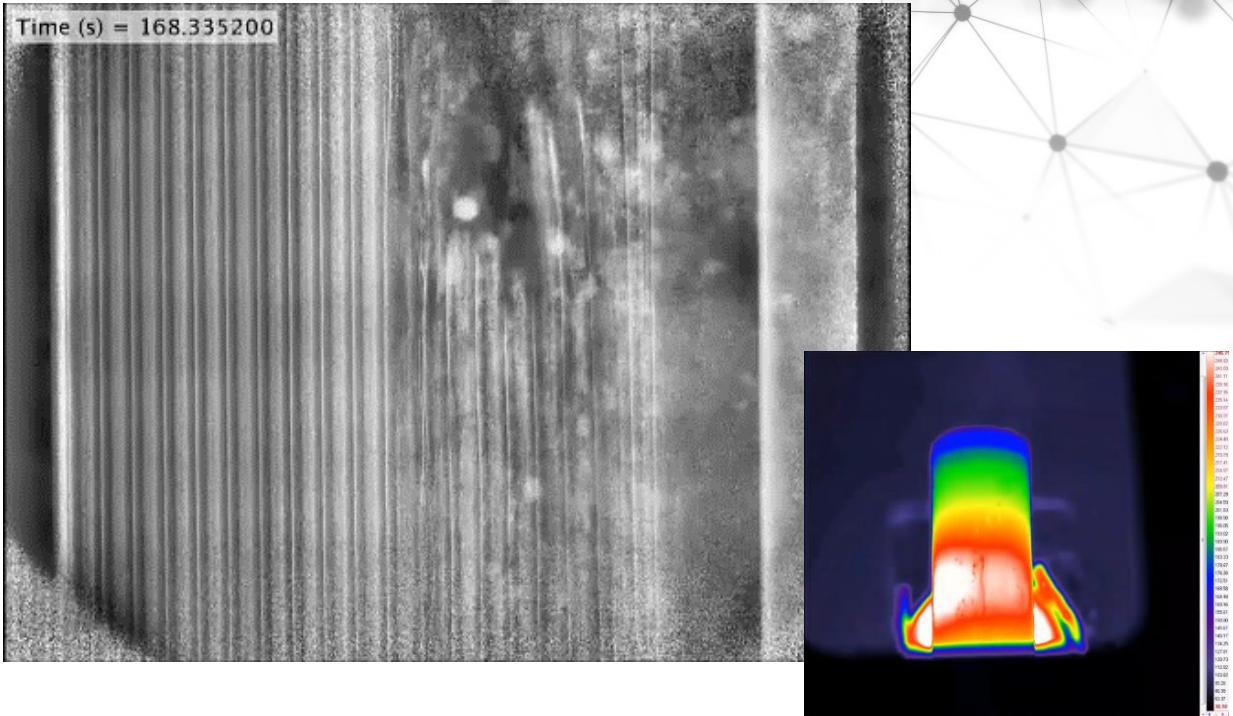
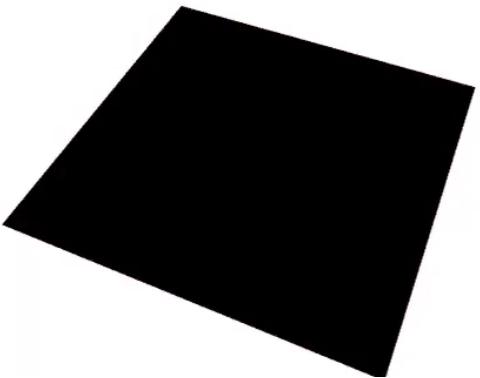
Gallinetti et al, Front. Bioeng. Biotechnol. (2016) DOI: 10.3389/conf.FBIOE.2016.01.00704

# Applications: Mechanical Failure

Delamination & failure of composite (cardboard)

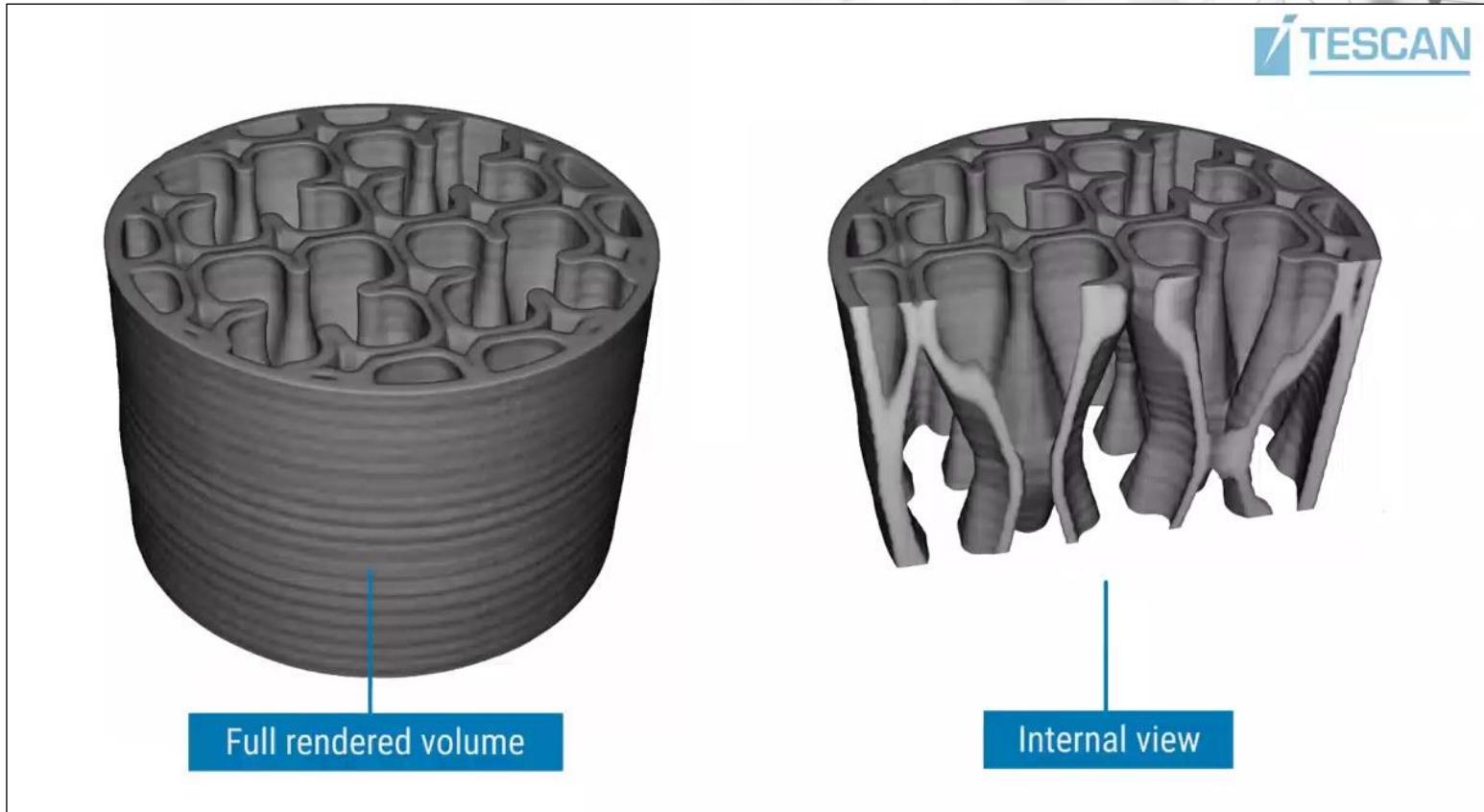


# Applications: AA Battery Runaway



Finegan et al, Nat Commun 6 (2015) 6924

# Applications: Part Optimization



# Applications

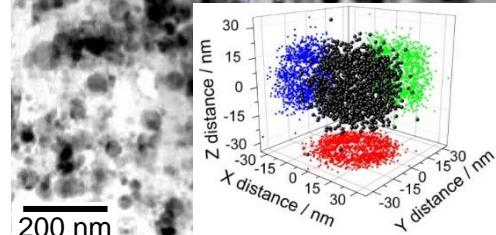
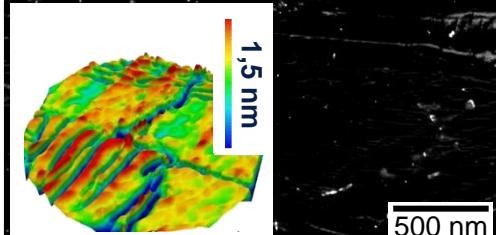
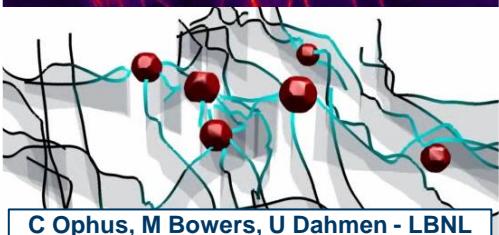
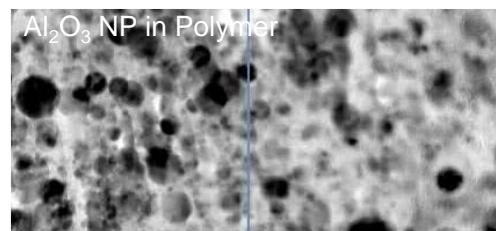
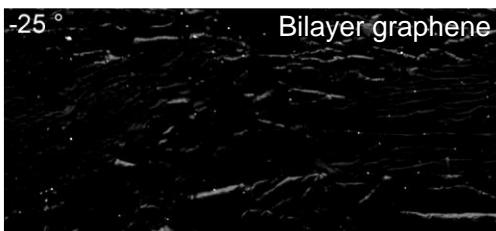
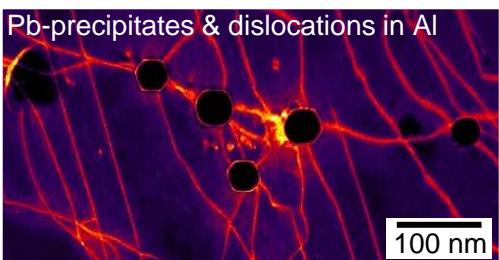
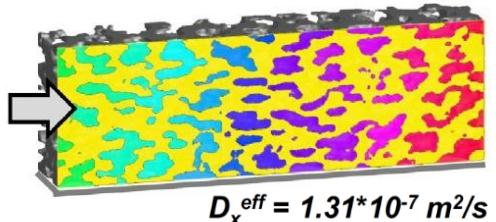
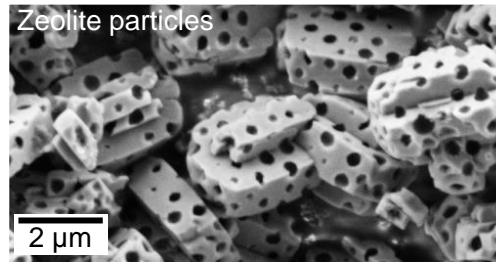
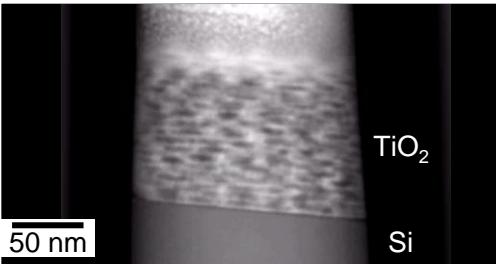
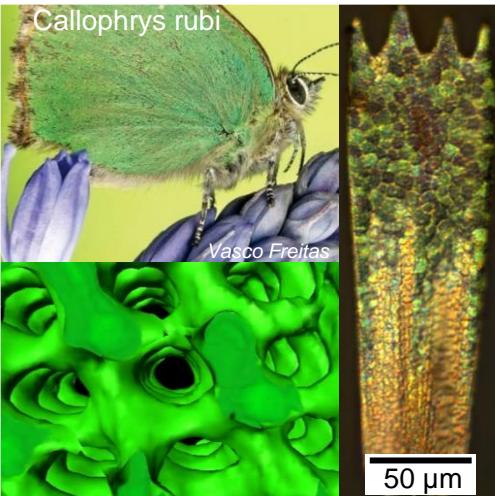
## Materials research

Morphology/  
structure  
formation

Phase  
distribution

Defects

...



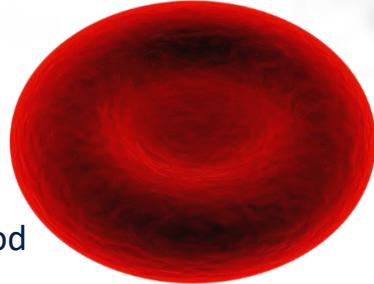
# Scales



Screw

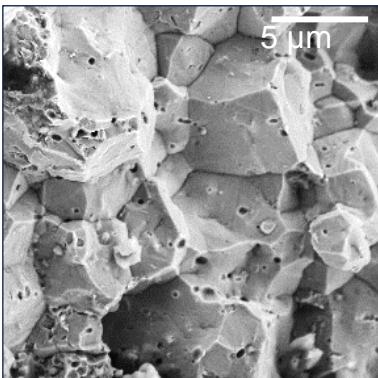


Circuit



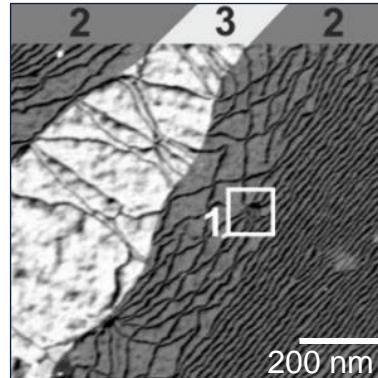
Red blood cell

Fracture surface



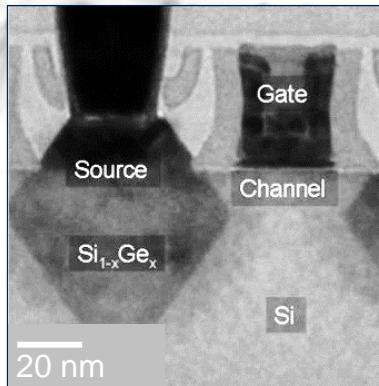
5  $\mu\text{m}$

Crystal defects

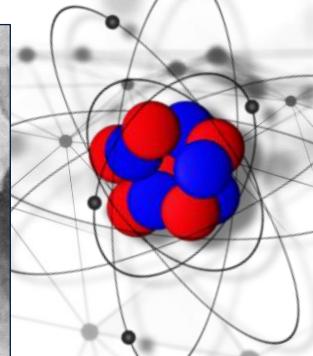


200 nm

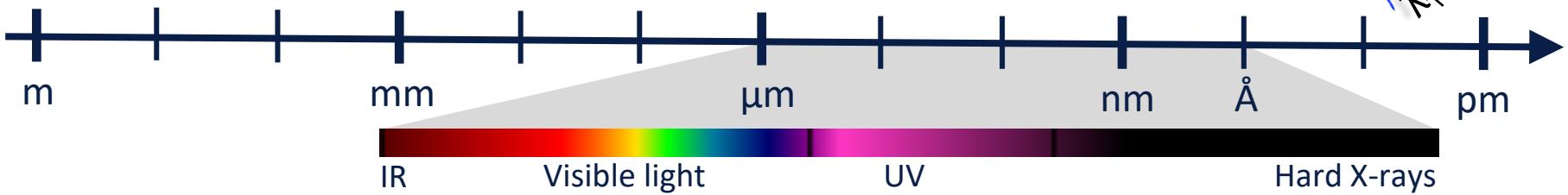
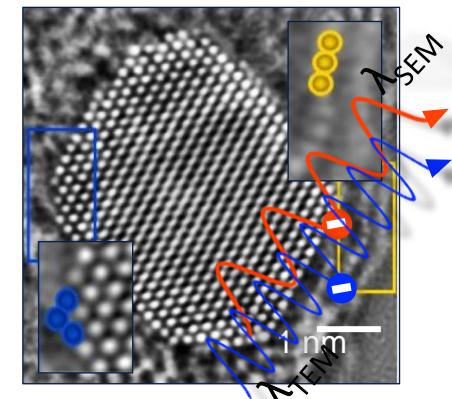
pFET



20 nm



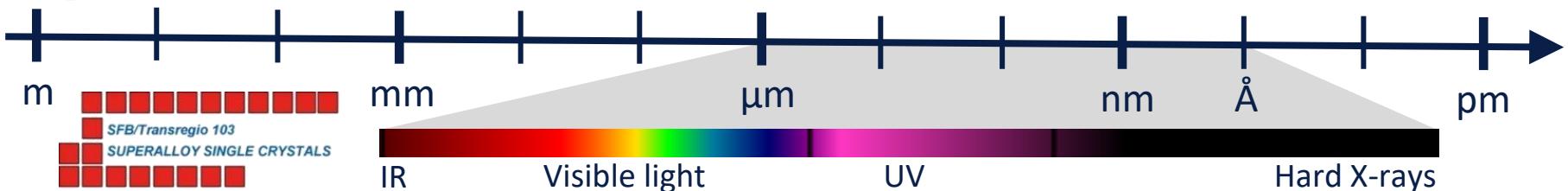
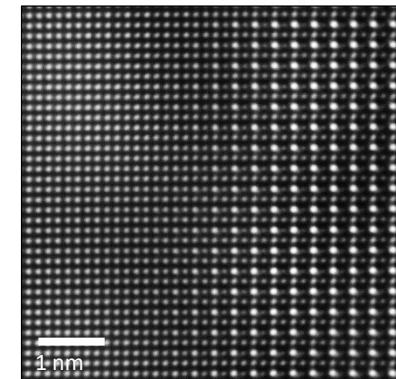
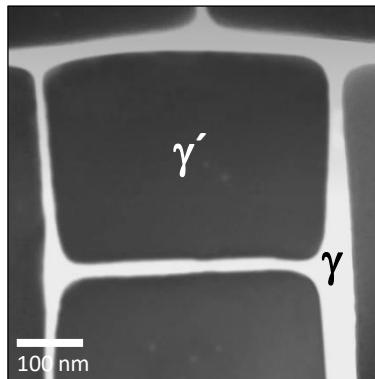
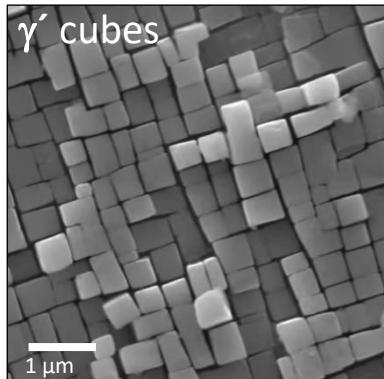
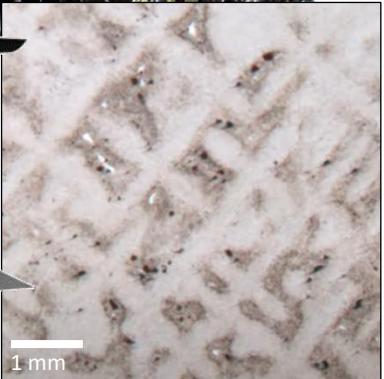
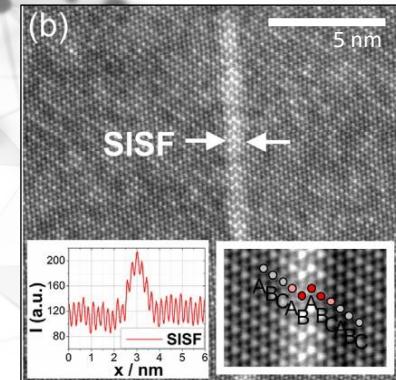
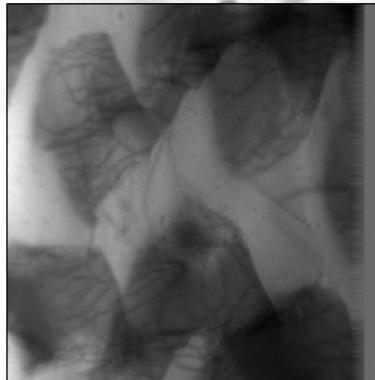
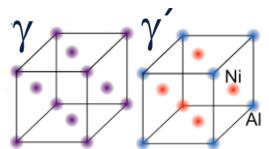
Pt-NP



# Scales

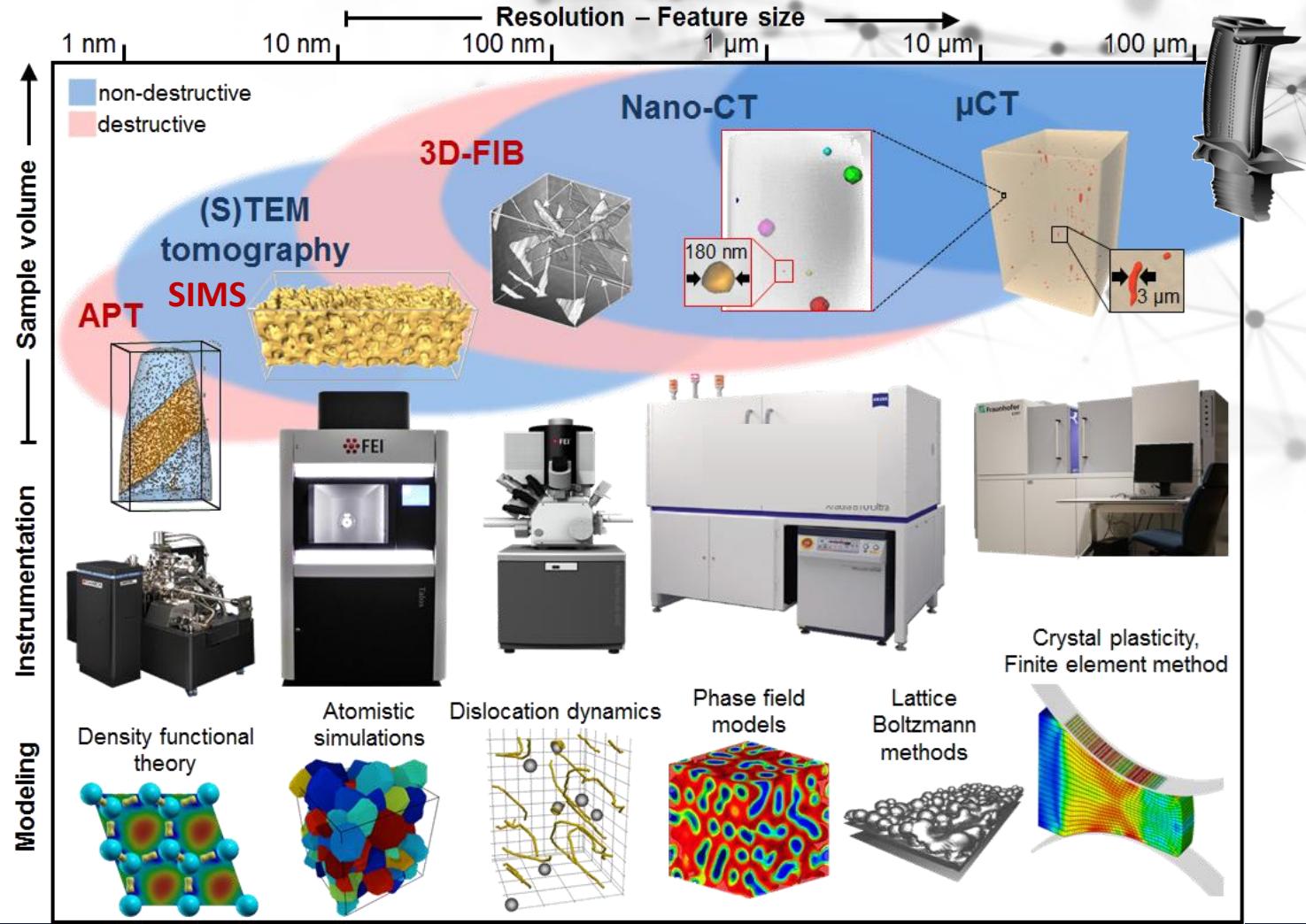


after creep deformation



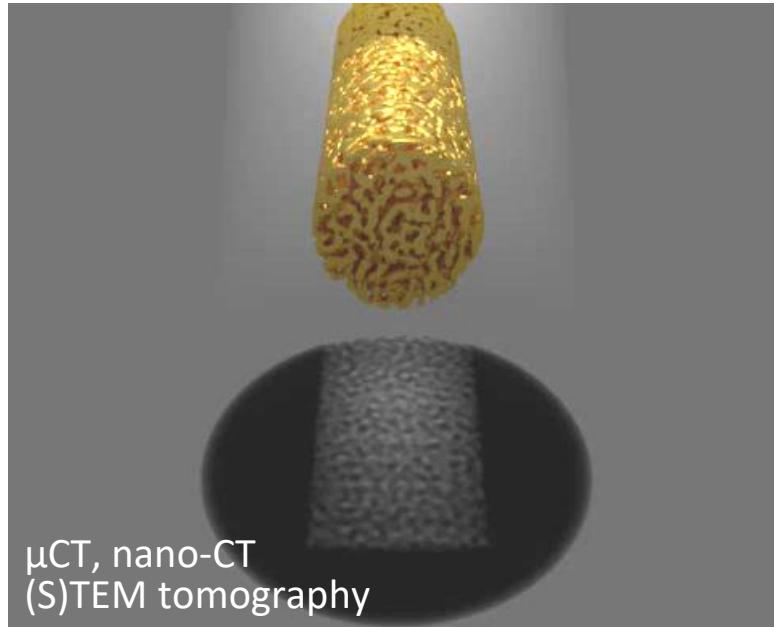
# Scale-bridging & Correlative Approach

3D-techniques  
for all  
length scales!

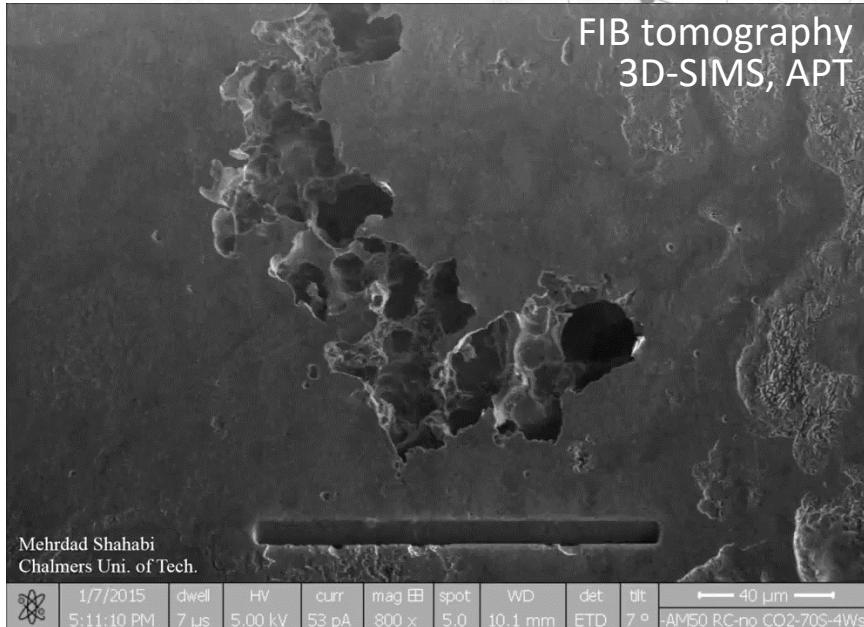


# Projection Tomography vs. Serial Sectioning

## Projection tomography



## Serial sectioning



Both techniques necessitate suited  
reconstruction algorithms!

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